


<b>Search Notes</b>  	<b>Application/Control No.</b>  10662470	<b>Applicant(s)/Patent Under Reexamination</b>  EKBERG, JAN-ERIK
	<b>Examiner</b>  Ho, Huy C	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
709	228	5/25/07	HH
370	338	5/25/07	HH
455	41.2	12/30/2008	HH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search in USPAT, US PGPUB, USOCR, JPO, DERWENT, IBM(See attached search strategy)	1/18/07	HH
Search update	5/25/07	HH
Search update	11/25/2007	HH
Search update	5/19/2008	HH
Search update	12/30/2008	HH
Consulted with SPE Nick Corsaro	12/30/2008	HH
Consulted with SPE Alexander Eisen	1/14/2009	HH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
455	41.2	12/30/2008	HH
709	227		

/HUY C HO/  
Examiner,Art Unit 2617